

**DEPARTMENT OF ELECTRONICS
FACULTY OF ELECTRICAL ENGINEERING
UNIVERSITI TEKNOLOGI MARA
SHAH ALAM**

**PHOTOCONDUCTIVITY STUDY OF TiO₂ THIN FILMS
ANNEALED IN OXYGEN AMBIENT**

Final Project submitted in partial fulfillment
of the requirement for the award of
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**PREPARED BY: ANIS ATAILLAH BT ISMAIL
SEMESTER: DECEMBER 2006-MAY 2010
STUDENT ID: 2006142151**

ABSTRACT

The main objective of this thesis is to present the research on photoconductivity of TiO₂ thin film annealed in oxygen ambient. Titanium dioxide thin films have been deposited on glass substrate by sol gel technique (dip coating method) at various oxygen flow rate. The electrical conductivity, surface morphology and optical properties of these thin films have been studied using Current Voltage (I-V) Measurement, SEM and UV-VIS-NIR Spectrophotometer, respectively. It is shown that in sol gel derived TiO₂ thin films the oxygen adsorption has a great influence on photoconductivity. The photoconductivity depends on the ambient environment. A UV-VIS-NIR spectrum reveals all films exhibit high transmission (50%) in UV-NIR region. From I-V measurement result, the electrical properties were studied in dark and under illumination as a function of oxygen flow rate. Introduction of oxygen in TiO₂ based coatings induces an increase of their electrical resistivity. The reduction hardness of TiO₂ thin films with increase of the oxygen flow rate is discussed based on film structure that shown by SEM.

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TABLE OF CONTENTS

Abstract	<i>i</i>
Acknowledgement	<i>ii</i>
Table of Contents	<i>iii</i>
List of Figures	<i>vi</i>
List of Tables	<i>vii</i>
List of Abbreviations	<i>vii</i>
CHAPTER 1	
GENERAL	
1.1 Introduction	1
1.2 Project Objectives	2
1.3 Scope of Research	2
1.4 Organization of the Thesis	2
CHAPTER 2	
THEORETICAL BACKGROUND	
2.1 Titanium	
2.1.1 Physical	4
2.1.2 Chemical	5
2.2 Titanium Dioxide	5
2.3 Sol Gel	6
2.4 Thin Films	8
2.5 Absorption	
2.5.1 Optical Absorption	9

CHAPTER 1: GENERAL

1.1 INTRODUCTION

TiO₂ films are extensively studied because of their interesting chemical, electrical and optical properties. TiO₂ is a high band gap semiconductor that is transparent to visible light and has excellent optical transmittance. TiO₂ has high refractive index and good insulating properties, and as a result it is widely used as protective layer for very large scale integrated (VLSI) circuits and for manufacture of optical elements.

Additionally TiO₂ films have potential uses for a number of electronic device applications such as dye-sensitized photovoltaic cells as well as antireflective (AR) coatings, gas sensors, electrochromic displays, and planar waveguides. The high dielectric constant of TiO₂ allows its consideration as an alternative to silicon dioxide for ultrathin gate oxide dielectrics used in memory and logic devices.

Several methods have been used to prepare titania films and these include chemical vapour deposition (CVD), pulsed laser deposition, reactive sputtering and sol-gel deposition. The sol-gel technique has emerged as one of the most promising techniques as this method produces samples with good homogeneity at low cost. To achieve optimum performance it is important to characterize the optical constants and thicknesses of thin TiO₂ layers accurately [1].